Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/747,370	LABARGE ET AL.	
Examiner	Art Unit	
Hien Tran	1764	

	SEAR	CHED	
Class	Subclass	Date	Examiner
422	177, 179, 180	6/23/2004	нт
updated	search	12/23/2004	нт
updated	search	3/13/06	нт
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
iEast Image class/subclass search / Inventors' names search /text search	6/23/2004	нт
updated search	3/13/2006	нт
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